**Product data sheet** 

# 1. General description

Planar passivated very sensitive gate four quadrant triac in a SOT223 surface-mountable plastic package intended for applications requiring enhanced immunity to noise and direct interfacing to logic level ICs and low power gate drivers.

### 2. Features and benefits

- · Direct interfacing to logic level ICs
- · Enhanced current surge capability
- Enhanced noise immunity
- High blocking voltage capability
- · Planar passivated for voltage ruggedness and reliability
- · Surface-mountable package
- Triggering in all four quadrants
- Very sensitive gate in four quadrants

## 3. Applications

- General purpose low power motor control
- Home appliances
- Industrial process control
- Low power AC Fan controllers

### 4. Quick reference data

Table 1. Quick reference data

| Symbol           | Parameter                                | Conditions  | Min | Тур | Max  | Unit |
|------------------|--|---|-----|-----|------|------|
| Absolute         | maximum rating                           |   |     |     |      |      |
| $V_{DRM}$        | repetitive peak off-state voltage        |   | -   | -   | 600  | V    |
| $I_{T(RMS)}$     | RMS on-state current                     | full sine wave; $T_{sp} \le 105 ^{\circ}\text{C}$ ;<br>Fig. 1; Fig. 2; Fig. 3           | -   | -   | 1    | А    |
| I <sub>TSM</sub> | non-repetitive peak on-<br>state current | full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 20 ms;<br>Fig. 4; Fig. 5                 | -   | -   | 12   | А    |
|                  |  | full sine wave; $T_{j(init)} = 25  ^{\circ}\text{C}$ ; $t_p = 16.7  \text{ms}$          | -   | -   | 13.8 | А    |
| T <sub>j</sub>   | junction temperature                     |   | -   | -   | 125  | °C   |
| Symbol           | Parameter                                | Conditions  | Min | Тур | Max  | Unit |
| Static ch        | aracteristics                            |   |     |     |      |      |
| I <sub>GT</sub>  | gate trigger current                     | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G+;$<br>$T_j = 25 \text{ °C; } Fig. 9$ | 0.2 | -   | 3    | mA   |
|                  |  | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$<br>$T_j = 25 \text{ °C; } Fig. 9$ | 0.2 | -   | 3    | mA   |

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| Symbol                | Parameter                             | Conditions  |  | Min | Тур | Max | Unit |  |  |
|-----------------------|---------------------------------------|---|--|-----|-----|-----|------|--|--|
| Static cha            | Static characteristics                |   |  |     |     |     |      |  |  |
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{ G-};$<br>$T_j = 25 \text{ °C}; Fig. 9$                         |  | 0.2 | -   | 3   | mA   |  |  |
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- G+; $<br>$T_j = 25 \text{ °C}; Fig. 9$                                |  | 0.2 | -   | 5   | mA   |  |  |
| I <sub>H</sub>        | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>   |  | -   | -   | 7   | mA   |  |  |
| V <sub>T</sub>        | on-state voltage                      | I <sub>T</sub> = 1.4 A; T <sub>j</sub> = 25 °C; <u>Fig. 12</u>  |  | -   | 1.3 | 1.6 | V    |  |  |
| Dynamic               | characteristics                       |   |  |     |     |     |      |  |  |
| dV <sub>D</sub> /dt   | rate of rise of off-state voltage     | $V_{DM}$ = 402 V; $T_j$ = 110 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit; Fig. 14 |  | 80  | -   | -   | V/µs |  |  |
| dV <sub>com</sub> /dt | rate of change of commutating voltage | $V_D = 400 \text{ V}; T_j = 110 ^{\circ}\text{C};$<br>$dI_{com}/dt = 0.44 \text{ A/ms}; gate open circuit}$         |  | 0.5 | -   | -   | V/µs |  |  |

# 5. Pinning information

#### **Table 2. Pinning information**

| Pin | Symbol | Description     | Simplified outline | Graphic symbol |
|-----|--------|-----------------|--------------------|----------------|
| 1   | T1     | main terminal 1 |                    | Z              |
| 2   | T2     | main terminal 2 |                    | T2 T1          |
| 3   | G      | gate            |                    | sym051         |
| 4   | T2     | main terminal 2 | 1 2 3              |                |
|     |        |                 |                    |                |

# 6. Ordering information

#### **Table 3. Ordering information**

| Type number | Package<br>Name | Orderable part number | Packing method | Small packing quantity | Package version | Package issue date |
|-------------|-----------------|-----------------------|----------------|------------------------|-----------------|--------------------|
| Z0103MN0    | SOT223          | Z0103MN0,135          | Reel           | 4000                   | SOT223          | 16-Mar-2006        |

# 7. Marking

### **Table 4. Marking codes**

| Type number | Marking codes       |                     |
|-------------|---------------------|---------------------|
|             | Assembly factory: d | Assembly factory: L |
| Z0103MN0    | Jdxxx<br>103MN0     | JLxxx<br>103MN0     |

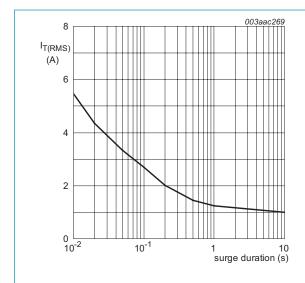
# 8. Limiting values

**Table 5. Limiting values** 

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol              | Parameter                                | Conditions  | Min | Max  | Unit             |
|---------------------|--|---|-----|------|------------------|
| $V_{DRM}$           | repetitive peak off-state voltage [1]    |   | -   | 600  | V                |
| I <sub>T(RMS)</sub> | RMS on-state current                     | full sine wave; $T_{sp} \le 105 ^{\circ}\text{C}$ ;<br>Fig 1; Fig 2; Fig 3              | -   | 1    | А                |
| I <sub>TSM</sub>    | non-repetitive peak on-<br>state current | full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 20 \text{ ms}$ ;<br>Fig 4; Fig 5 | -   | 12   | А                |
|                     |  | full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 16.7 ms                                  | -   | 13.8 | А                |
| l <sup>2</sup> t    | I <sup>2</sup> t for fusing              | t <sub>p</sub> = 10 ms; SIN   | -   | 0.78 | A <sup>2</sup> s |
| dl <sub>⊤</sub> /dt | rate of rise of on-state current         | I <sub>G</sub> = 20 mA; T2+ G+  | -   | 50   | A/µs             |
|                     |  | I <sub>G</sub> = 20 mA; T2+ G-  | -   | 50   | A/µs             |
|                     |  | I <sub>G</sub> = 20 mA; T2- G-  | -   | 50   | A/µs             |
|                     |  | I <sub>G</sub> = 20 mA; T2- G+  | -   | 20   | A/µs             |
| I <sub>GM</sub>     | peak gate current                        |   | -   | 1    | А                |
| $P_{\text{GM}}$     | peak gate power                          |   | -   | 2    | W                |
| $P_{G(AV)}$         | average gate power                       | over any 20 ms period   | -   | 0.1  | W                |
| T <sub>stg</sub>    | storage temperature                      |   | -40 | 150  | °C               |
| T <sub>j</sub>      | junction temperature                     |   | -   | 125  | °C               |

[1] Although not recommended, off-state voltage up to  $V_{DRM}$  may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed  $3A/\mu s$ .



f = 50 Hz; T<sub>sp</sub> = 105 °C Fig. 1. RMS on-state current as a function of surge duration; maximum values

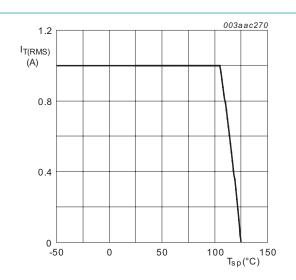
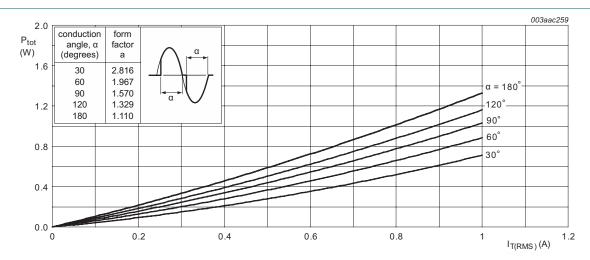


Fig. 2. RMS on-state current as a function of solder point temperature; maximum values

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 $\alpha$  = conduction angle

a = form factor =  $I_{T(RMS)} / I_{T(AV)}$ 

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

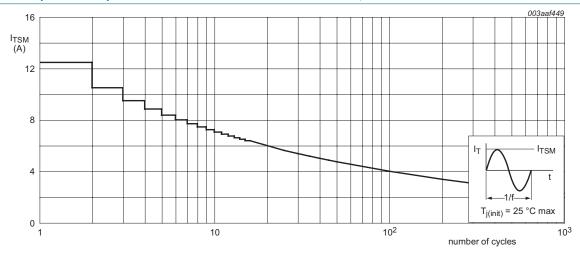
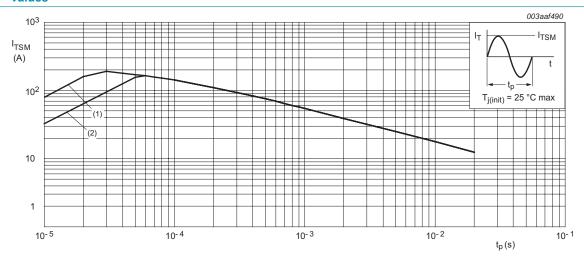


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



 $t_p \le 20 \text{ ms}$ 

(1) dl<sub>T</sub>/dt limit

(2) T2- G+ quadrant limit

Fig. 5. Non-repetitive peak on-state current as a function of pulse width; maximum values

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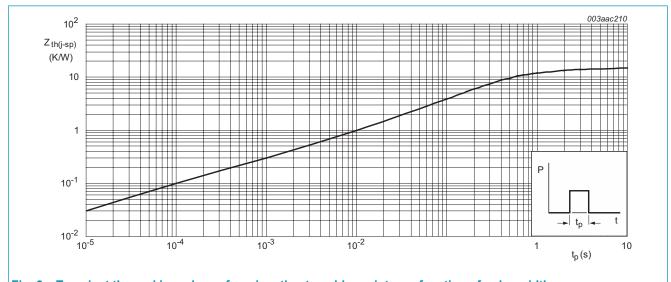
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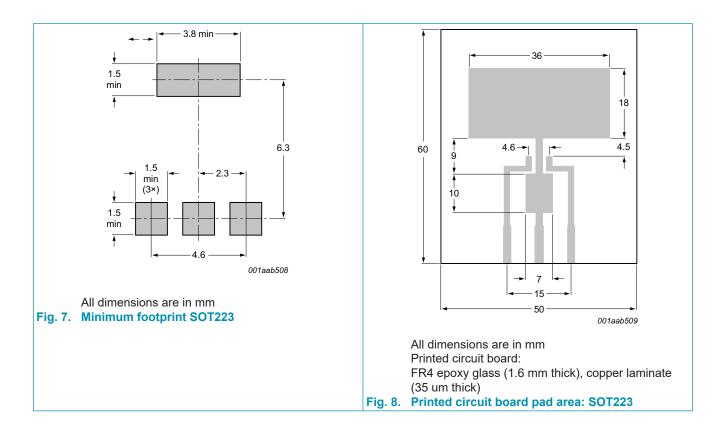
## 9. Thermal characteristics

**Table 6. Thermal characteristics** 

| Symbol                | Parameter  | Conditions   | Min | Тур | Max | Unit |
|-----------------------|--|--|-----|-----|-----|------|
| $R_{\text{th(j-sp)}}$ | thermal resistance<br>from junction to solder<br>point | full cycle; Fig 6  | -   | -   | 15  | K/W  |
| R <sub>th(j-a)</sub>  | thermal resistance from junction to                    | in free air; printed circuit board mounted; minimum footprint; full cycle; Fig 7 | -   | 156 | -   | K/W  |
|                       | ambient  | in free air; printed circuit board mounted; pad area; full cycle; Fig 8          | -   | 70  | -   | K/W  |



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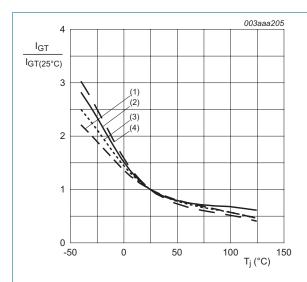
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# 10. Characteristics

### **Table 7. Characteristics**

| Symbol                | Parameter                             | Conditions  | Min | Тур | Max | Unit |
|-----------------------|---------------------------------------|---|-----|-----|-----|------|
| Static cha            | aracteristics                         |   |     |     | ,   |      |
| l <sub>GT</sub>       | gate trigger current                  | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+; T_j = 25 °C; Fig. 9$  | 0.2 | -   | 3   | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G-;$<br>$T_j = 25 \text{ °C}; Fig. 9$                                 | 0.2 | -   | 3   | mA   |
|                       |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2\text{- G-;} $<br>$T_j = 25 \text{ °C; } \underline{\text{Fig. 9}}$   | 0.2 | -   | 3   | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- G+; $<br>$T_j = 25 \text{ °C}; Fig. 9$                                | 0.2 | -   | 5   | mA   |
| I <sub>L</sub>        | latching current                      | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$<br>$T_j = 25 \text{ °C}; Fig. 10$                                | -   | -   | 7   | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G-;$<br>$T_j = 25 \text{ °C}; Fig. 10$                                | -   | -   | 20  | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$<br>$T_j = 25 \text{ °C}; \underline{\text{Fig. } 10}$    | -   | -   | 7   | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2- G+;$<br>$T_j = 25 \text{ °C}; Fig. 10$                                | -   | -   | 7   | mA   |
| I <sub>H</sub>        | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>   | -   | -   | 7   | mA   |
| V <sub>T</sub>        | on-state voltage                      | I <sub>T</sub> = 1.4 A; T <sub>j</sub> = 25 °C; <u>Fig. 12</u>  | -   | 1.3 | 1.6 | V    |
| $V_{GT}$              | gate trigger voltage                  | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$<br>Fig. 13  | -   | -   | 1   | V    |
|                       |                                       | V <sub>D</sub> = 600 V; I <sub>T</sub> = 0.1 A; T <sub>j</sub> = 125 °C   | 0.2 | -   | -   | V    |
| I <sub>D</sub>        | off-state current                     | V <sub>D</sub> = 600 V; T <sub>j</sub> = 125 °C   | -   | -   | 0.5 | mA   |
| Dynamic               | characteristics                       |   |     |     |     |      |
| dV <sub>D</sub> /dt   | rate of rise of off-state voltage     | $V_{DM}$ = 402 V; $T_j$ = 110 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit; Fig. 14 | 80  | -   | -   | V/µs |
| dV <sub>com</sub> /dt | rate of change of commutating voltage | $V_D = 400 \text{ V}; T_j = 110 ^{\circ}\text{C};$<br>$dI_{com}/dt = 0.44 \text{ A/ms}; \text{ gate open circuit}$  | 0.5 | -   | -   | V/µs |

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- (2) T2- G-
- (3) T2+ G-
- (4) T2+ G+

Fig. 9. Normalized gate trigger current as a function of junction temperature

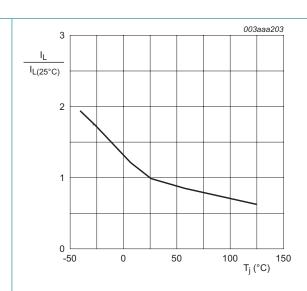


Fig. 10. Normalized latching current as a function of junction temperature

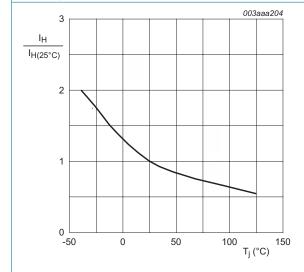
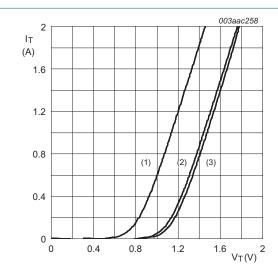


Fig. 11. Normalized holding current as a function of junction temperature



 $V_0 = 1.13 \text{ V}; R_s = 0.31 \Omega$ 

(1) T<sub>j</sub> = 125 °C; typical values (2) T<sub>j</sub> = 125 °C; maximum values

(3) T<sub>i</sub> = 25 °C; maximum values

Fig. 12. On-state current as a function of on-state voltage

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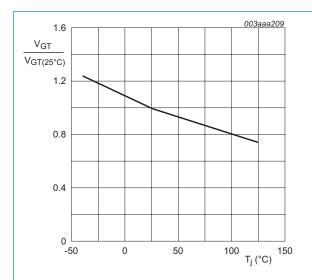


Fig. 13. Normalized gate trigger voltage as a function of junction temperature

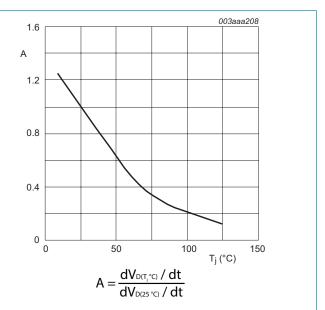
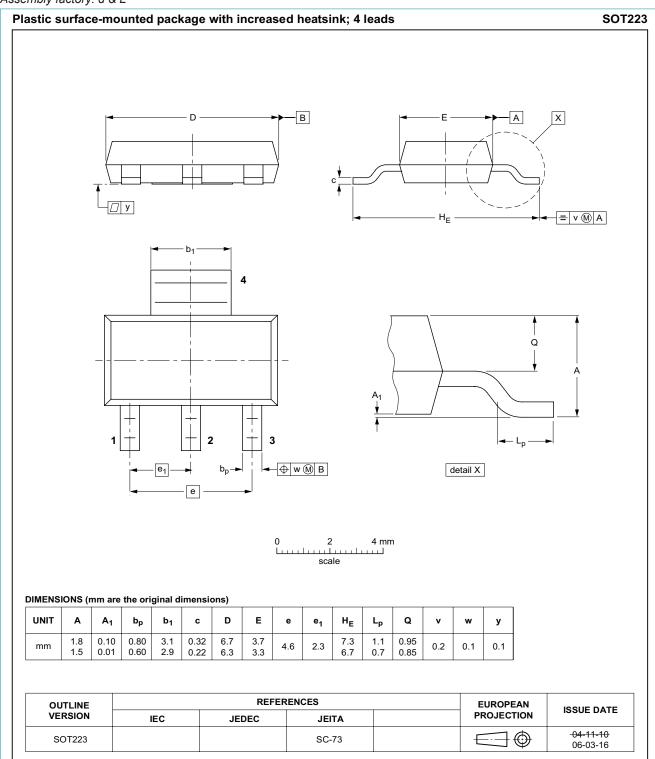


Fig. 14. Normalized critical rate of rise of off-state voltage as a function of junction temperature; typical values

# 11. Package outline

Assembly factory: d & L



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## 12. Legal information

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| Document status [1][2]               | Product status [3] | Definition  |
|--------------------------------------|--------------------|---|
| Objective<br>[short] data<br>sheet   | Development        | This document contains data from the objective specification for product development. |
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Date of release: 22 February 2022

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